

<b>Notice of References Cited</b>		Application/Control No. 10/579,732	Applicant(s)/Patent Under Reexamination INOUE ET AL.	
		Examiner JOSEPH DEAN, JR	Art Unit 4154	Page 1 of 1

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*	C US-2004/0137901	07-2004	Hamasaki et al.	455/436
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**NON-PATENT DOCUMENTS**

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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